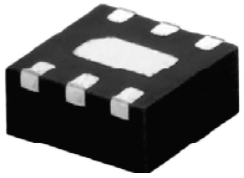
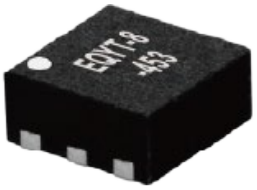
EQYT-8-453
Preliminary Datasheet
Gain Equalizer 50Ω 8dB DC-45GHz

A0

Features

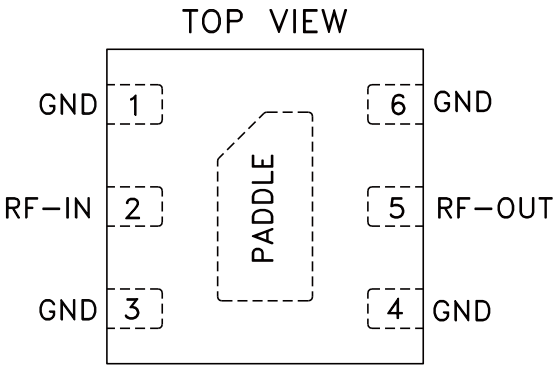
- 8.2 dB Slope
- Negative Insertion Loss Slope vs. Frequency
- Wideband operation, DC to 45 GHz
- Excellent Power Handling Capability
- Small Size and simple to use (2 mm x 2 mm)
- Human Body Model (HBM): Class 2 (Pass 2000V)
- Moisture Sensitivity: MSL1





RoHS

REACH COMPLIANT



Applications

- Cellular Infrastructure
- 5G
- Wideband Communications
- Test Instrumentation
- Defense

Electrical specifications at 25℃

Parameter	Condition (GHz)	Min.	Typ.	Max.	Units
Frequency Range		DC		45	GHz
Insertion Loss	0.01	9.1	9.4	9.7	dB
	10	7.5	7.9	8.1	
	20	-	5.3	-	
	30	2.4	3.0	3.4	
	40	-	1.5	-	
	45	-	1.2	-	
VSWR)	0.01-10	-	1.25	-	:1
	10-20	-	1.13	-	
	20-30	-	1.17	-	
	30-40	-	1.23	-	
	40-45	-	1.33	-	
*Input RF Power	27				dBm
Operating & Storage Condition Operation Temperature Range: -55℃ ~ +105℃ Storage Temperature Range: -65℃ ~ +150℃					

*Derates linearly to +24 dBm at 105°C

Yantel Corporation
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For detailed performance specs & shopping online see Yantel web site : www.yantel-corp.com

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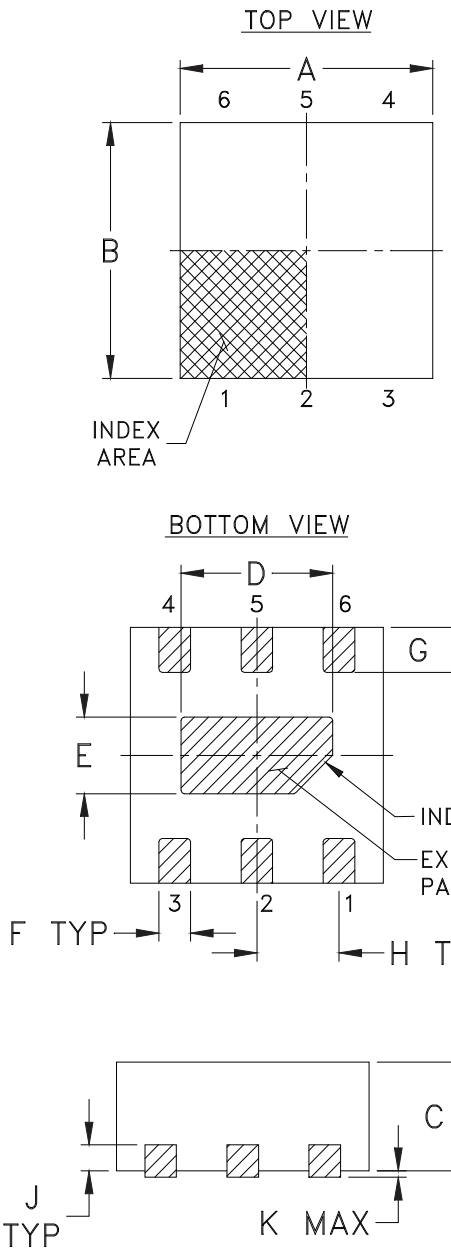
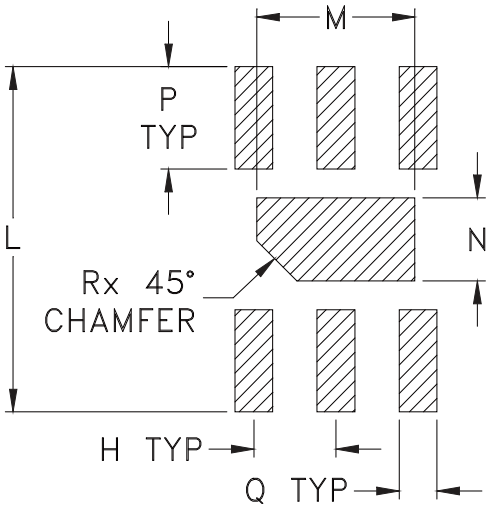
Outline Drawing



PCB Land Pattern



A	B	C	D	E	F	G	H	J	K	L	M
.079 (2.00)	.079 (2.00)	.039 (1.00)	.047 (1.20)	.024 (.60)	.010 (.25)	.014 (.35)	.026 (.65)	.008 (.20)	.002 (.05)	.106 (2.70)	.049 (1.25)
N	P	Q	R	WT, GRAM							
.026 (.65)	.031 (.80)	.012 (.30)	.012 (.30)	.006							

Units= inches (mm)

Tolerances=±.001 (±.25)

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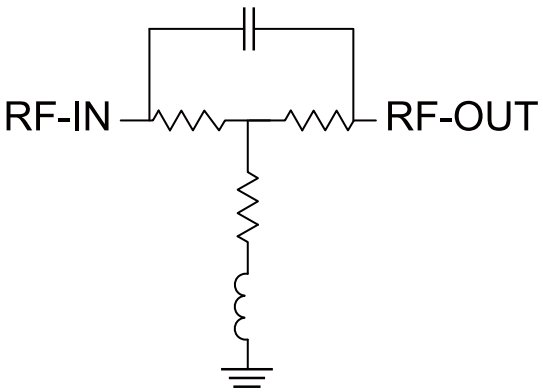
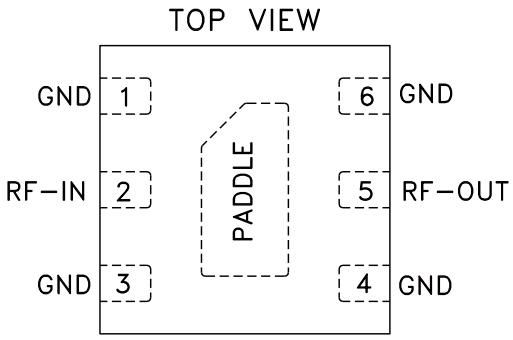
Simplified Schematic And Pad Description





Function	Pad Number	Description
RF-IN	2	RF-Input pad
RF-OUT	5	RF-Output pad
GND	1,3,4,6 & Paddle	Ground

Characterization Test Circuit